Notice of References Cited Application/Control No. 10/829,649 Examiner BRIAN P. YENKE Applicant(s)/Patent Under Reexamination ONOMATSU, TAKEHIRO Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	.А	US-7,023,491	04-2006	Sirilla, George Andrew	348/559
*	В	US-6,477,312	11-2002	Houston, Theodore W.	386/46
*	С	US-6,441,862	08-2002	Yuen et al.	348/565
*	D	US-6,363,213	03-2002	Sparks et al.	386/112
*	Ε	US-6,112,007	08-2000	Kram, Christine	386/46
*	F	US-7,065,287	06-2006	Heredia et al.	386/52
*	G	US-5,420,642	05-1995	Baek, Woon K.	348/565
*	Н	US-5,913,009	06-1999	Kuboji et al.	386/68
*	1	US-5,572,260	11-1996	Onishi et al.	348/460
*	J	US-6,941,574	09-2005	Broadwin et al.	725/37
*	К	US-6,427,048	07-2002	Ito et al.	386/95
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
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	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Vol	ume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.